

Fig. 1

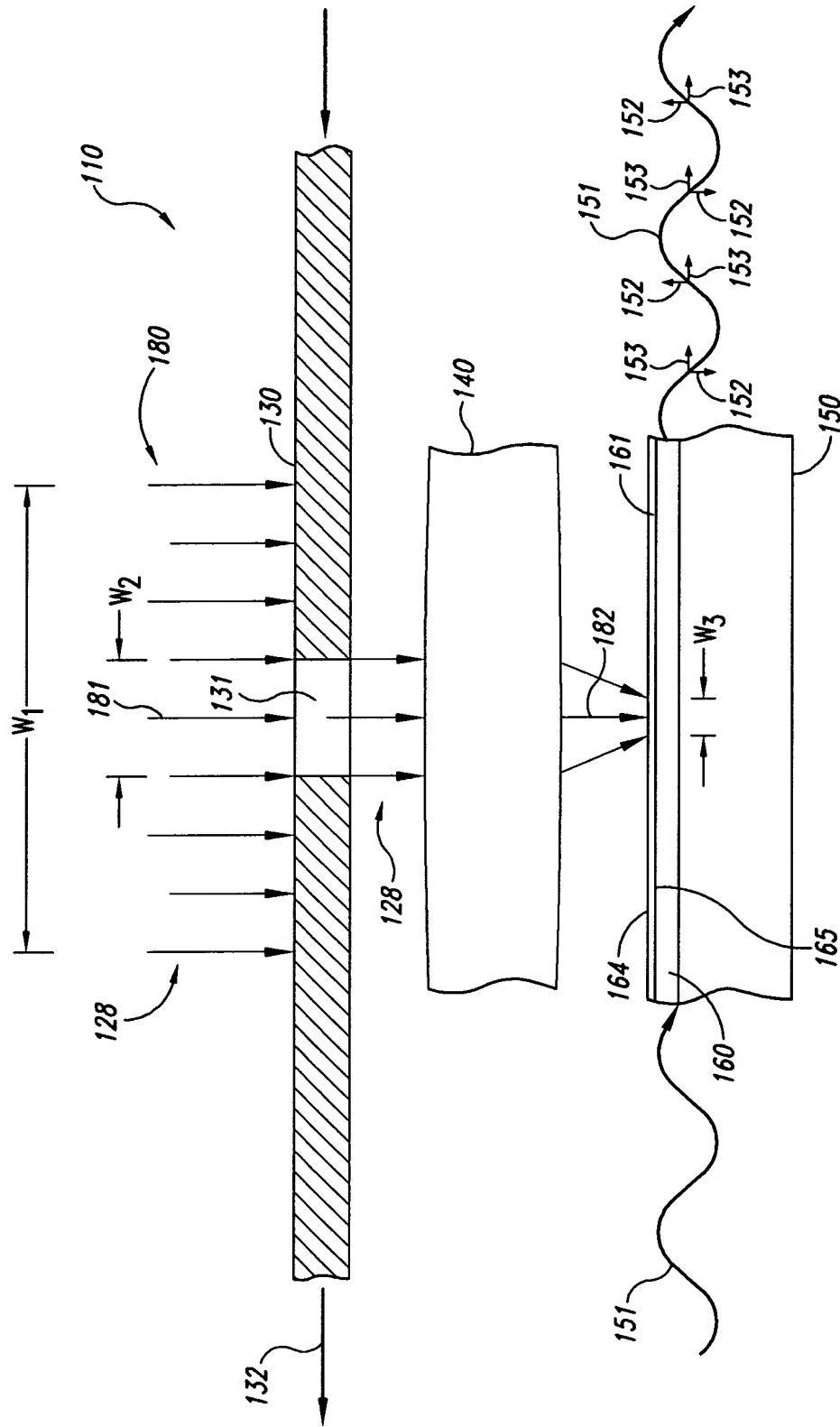


Fig. 2

A graph showing the axial position of a microelectronic substrate relative to the focal plane (Y-axis) as a function of its transverse position (X-axis). The Y-axis is labeled "AXIAL POSITION OF MICROELECTRONIC SUBSTRATE RELATIVE TO FOCAL PLANE/DEGREE OF FOCUS" and has a central horizontal line with '+' signs at the top and bottom. The X-axis is labeled "TRANSVERSE POSITION OF MICROELECTRONIC SUBSTRATE (NORMALIZED TO MOTION RELATIVE TO BEAM OF ONE BEAM WIDTH (w_3) AT THE MICROELECTRONIC SUBSTRATE)" and has tick marks at -1, 0, 1, and 2. A sinusoidal wave, labeled 151a, oscillates around the zero line. The period of the wave is indicated by a double-headed arrow above the X-axis between two vertical dashed lines at x=0 and x=1, labeled $3/5 w_3$.

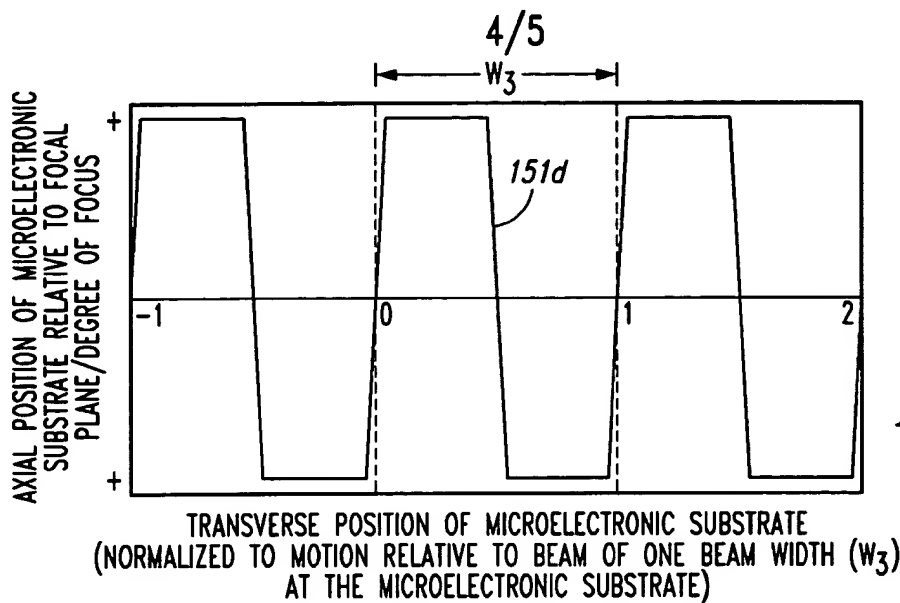


Fig. 3D

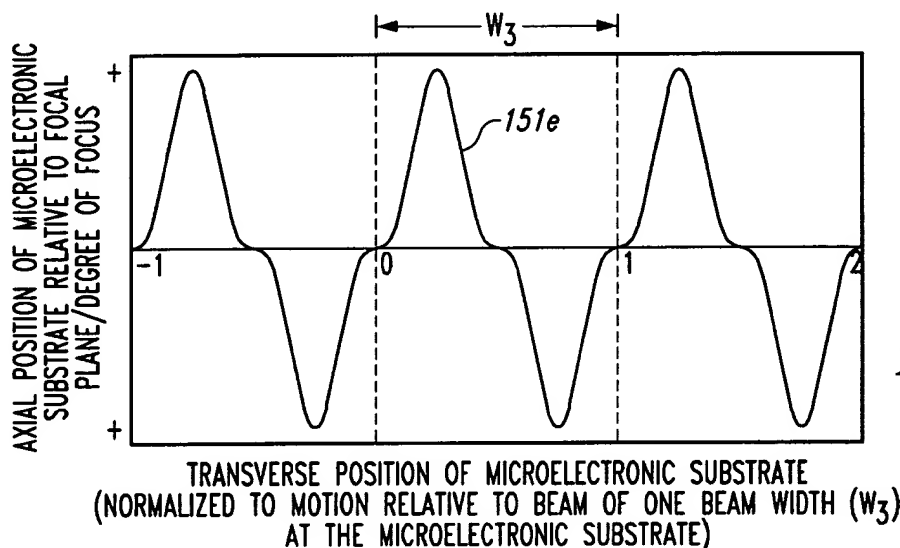


Fig. 3E

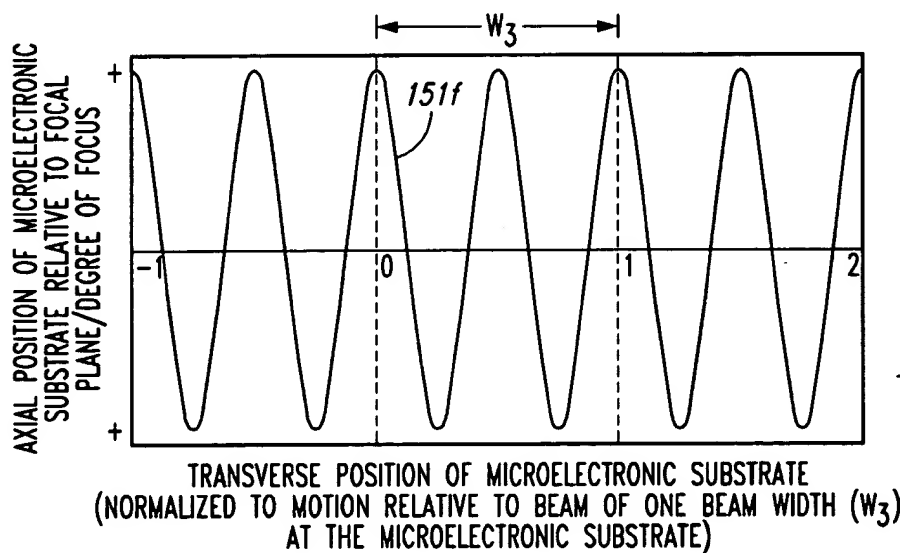


Fig. 3F

5/5

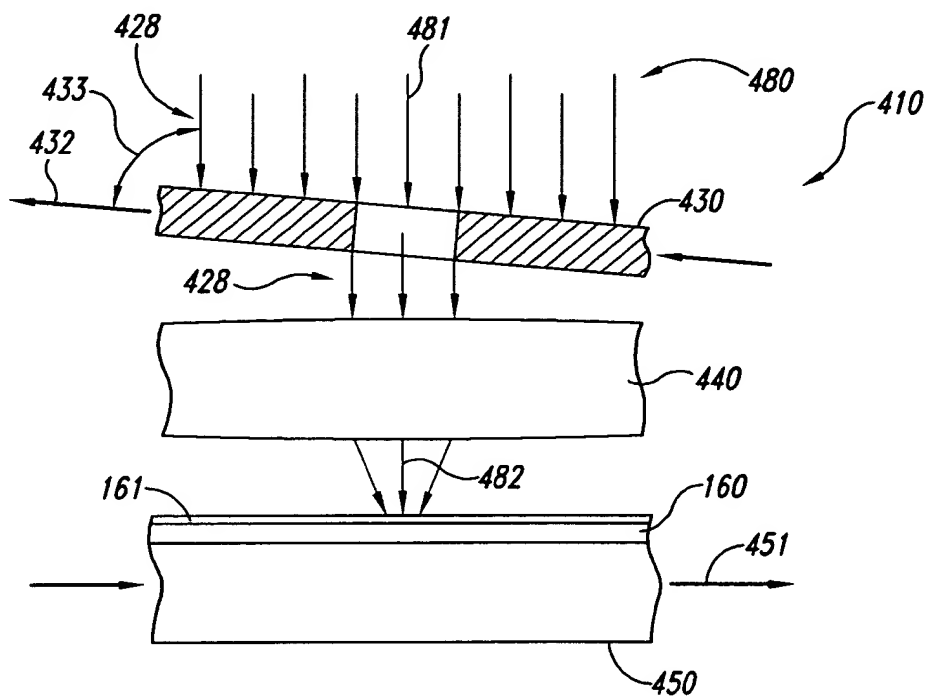


Fig. 4

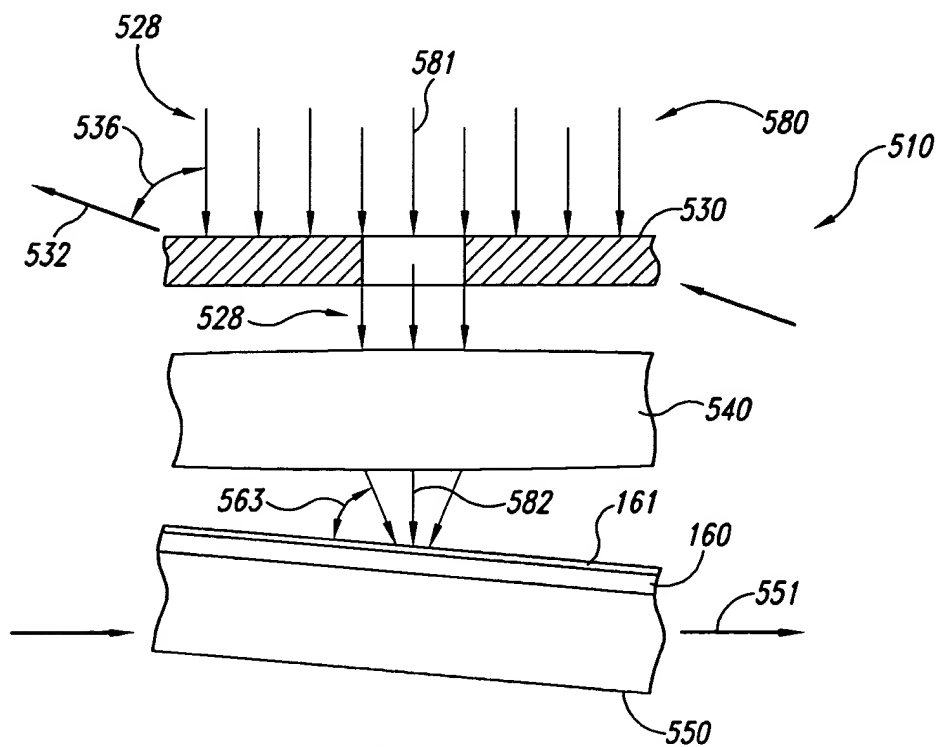


Fig. 5